

## Notice of References Cited

Application/Control No.

09/910,206

Applicant(s)/Patent Under

Reexamination

BEUTEN ET AL.

Examiner

Satish S. Rampuria

Art Unit

2124

Page 1 of 2

### U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,502,209 B1	12-2002	Bengtsson et al.	714/35
B	US-6,697,972 B1	02-2004	Oshima et al.	714/55
C	US-6,535,811 B1	03-2003	Rowland et al.	701/115
D	US-5,630,045 A	05-1997	Krygowski et al.	714/10
E	US-5,809,293 A	09-1998	Bridges et al.	712/227
F	US-6,282,701 B1	08-2001	Wygodny et al.	717/125
G	US-5,680,620	10-1997	Ross, S. Timothy	717/129
H	US-6,634,020 B1	10-2003	Bates et al.	717/131
I	US-6,658,653 B1	12-2003	Bates et al.	717/131
J	US-6,667,917 b1	12-2003	Templeton et al.	365/201
K	US-6,681,384 B1	01-2004	Bates et al.	717/129
L	US-6,560,722 B1	05-2003	Frankel et al.	714/38
M	US-6,463,553 B1	10-2002	Edwards, David Alan	714/38

### FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

### NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
U	Daniel Mann, Lowering the cost of software tracing, Electronic Engineering Times, Feb 5, 1996. pg. 72		
V	Warren Webb, Squash your embedded debugging time, EDN, Oct 14, 1999. Vol. 44, Iss. 21; p. 113 (6 pages)		
W	Nat Hillary, Interactive trace exposes bugs faster, Electronic Engineering Times, Manhasset: Mar 27, 2000. p. 110 (2 pages)		
X			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No. 09/910,206	Applicant(s)/Patent Under Reexamination BEUTEN ET AL.	
		Examiner Satish S. Rampuria	Art Unit 2124	Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,397,349 B2	05-2002	Higgins et al.	714/7
	B	US-6,145,123 A	11-2000	Torrey et al.	717/128
	C	US-5,983,017 A	11-1999	Kemp et al.	717/129
	D	US-5,943,498 A	08-1999	Yano et al.	717/128
	E	US-5,770,836 A	06-1998	Weiss, John	219/481
	F	US-5,657,442	08-1997	Groves, Andrew	714/28
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.